

Stochastic multiscale modeling of stiction failure in MEMS

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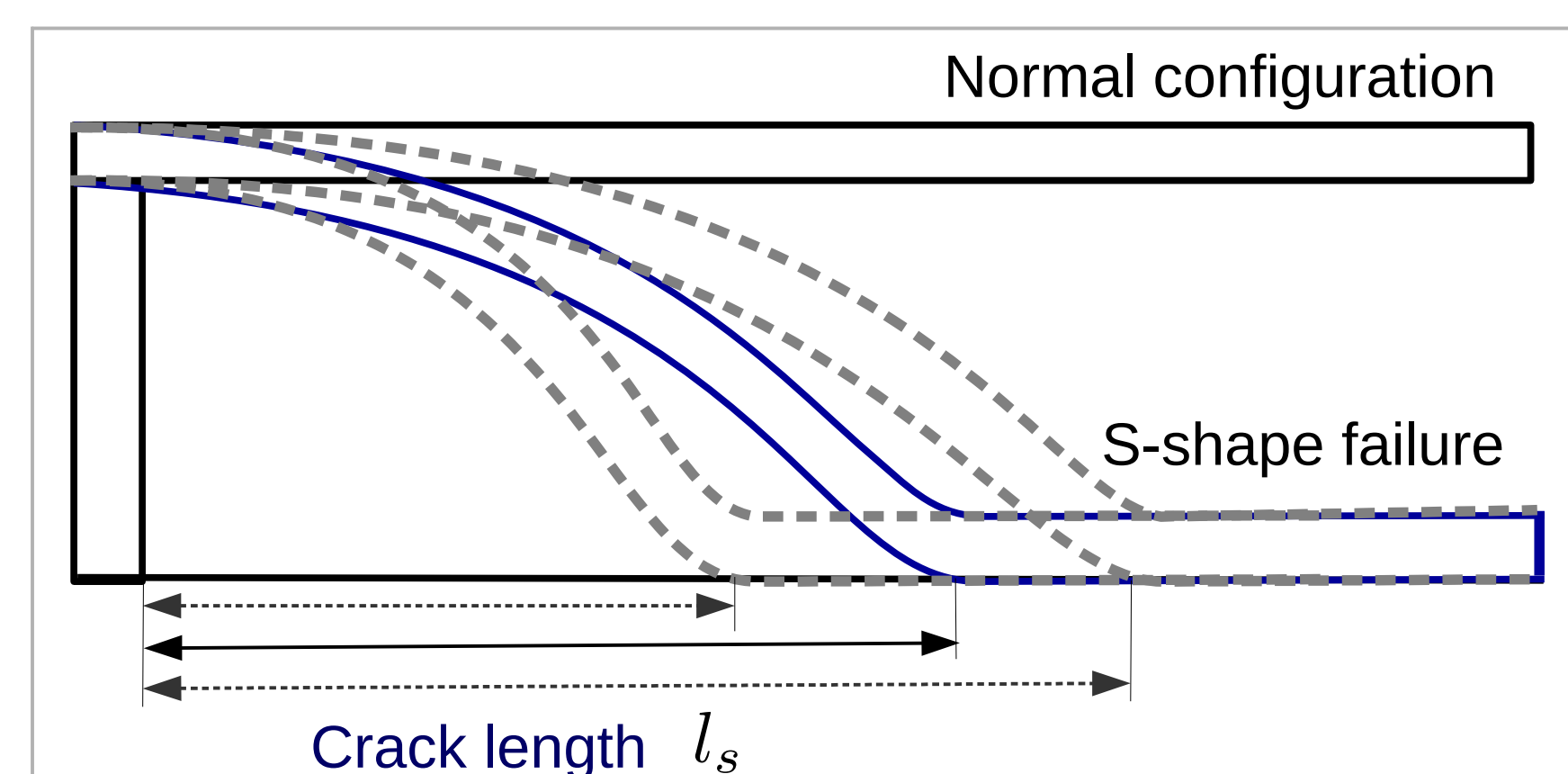
Introduction

- **Stiction** is a common failures in MEMS, in which two micro surfaces permanently adhere together, e.g. the stiction failure of micro cantilever beams.
- The problem is due to the adhesive forces, e.g. the **capillary forces**.
- The **adhesive contact force**, and **structural behaviors** suffer from **scatters**, due to the **roughness** of the contacting surfaces.

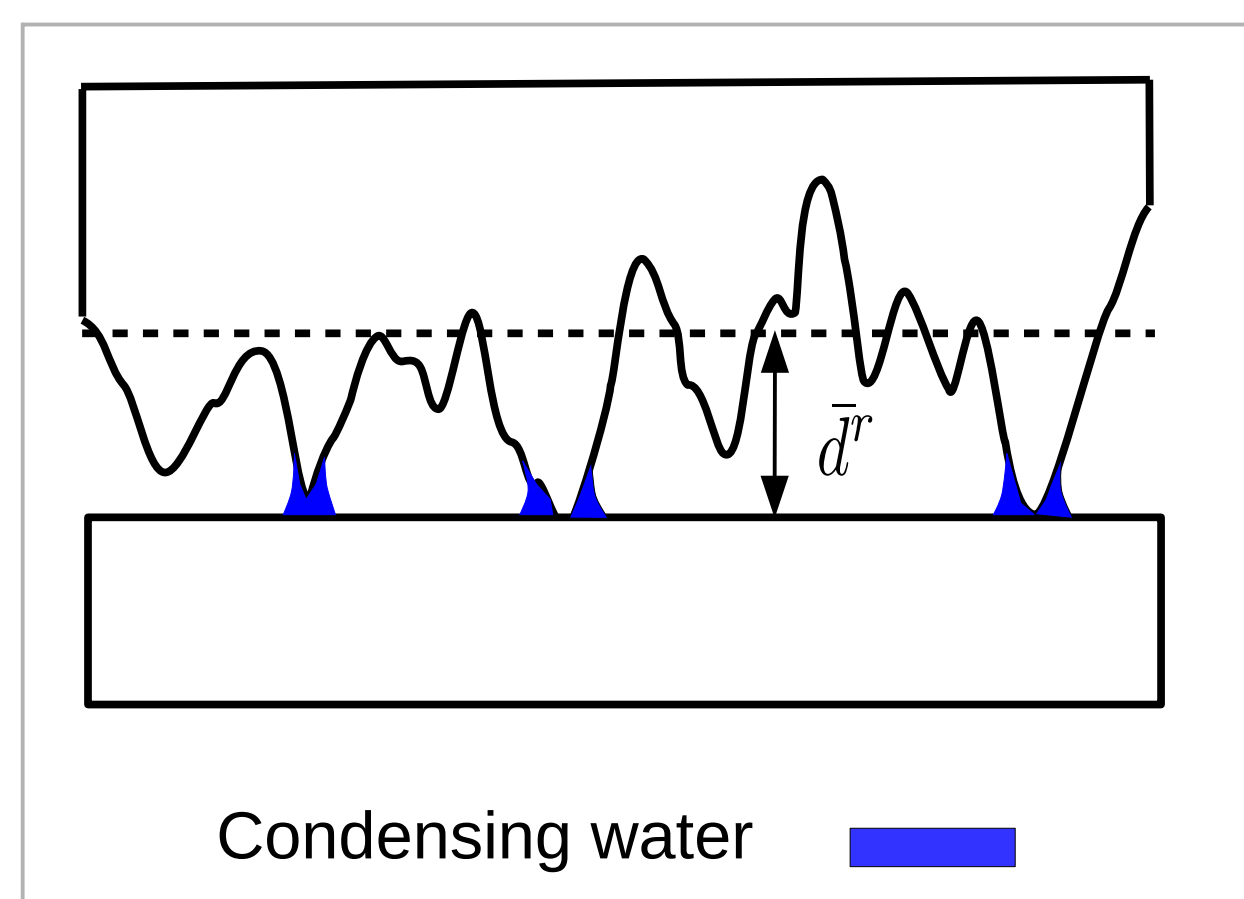
Aim

Construct a **numerical model**

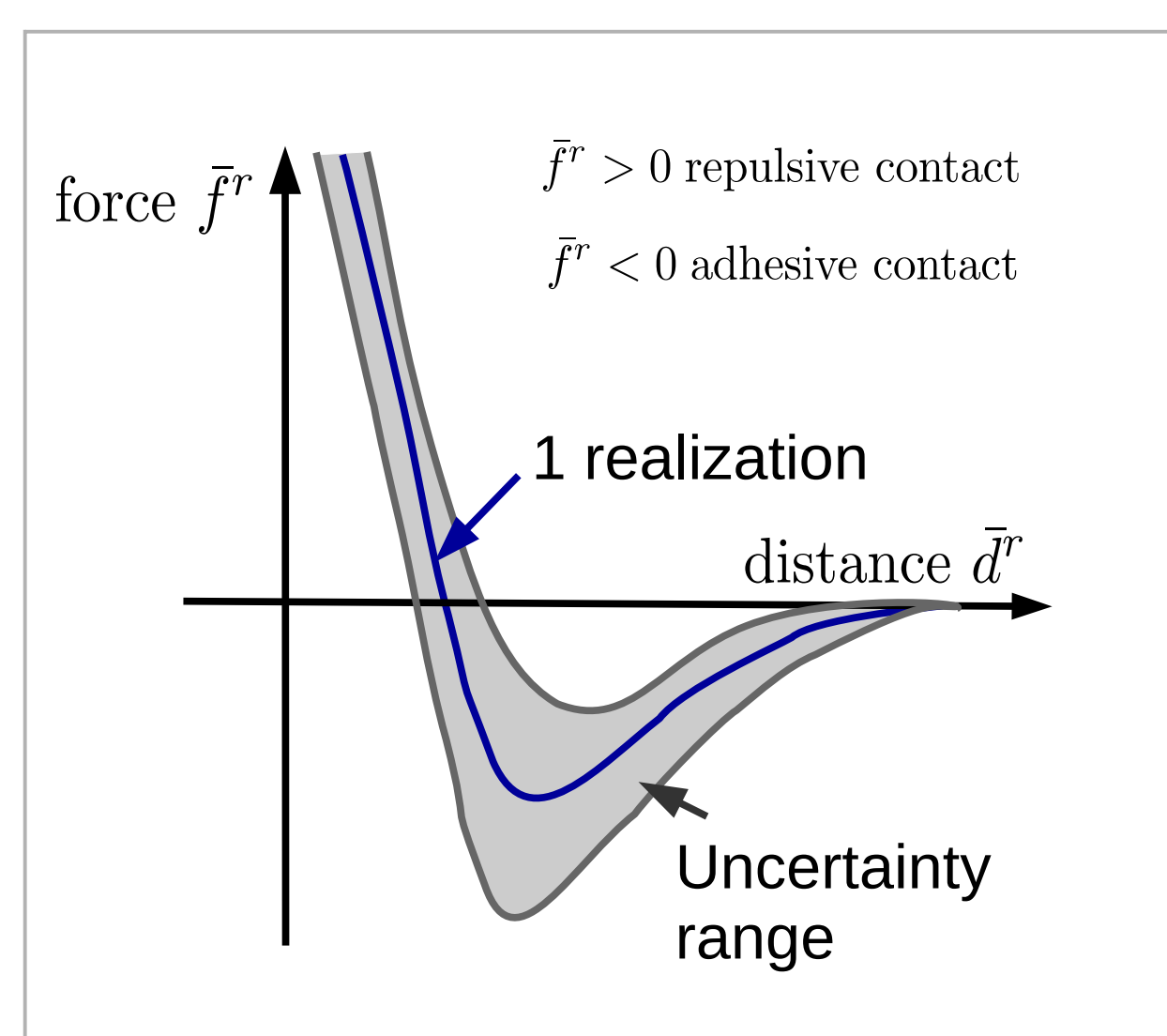
- to predict the **failure of MEMS devices** subject to adhesive stiction in a **probabilistic way**, e.g. to predict the probability of crack length in case of stiction failure of micro cantilever beam; and
- with an **acceptable computational cost**.



Failure of micro cantilever beams. The crack lengths are uncertain.



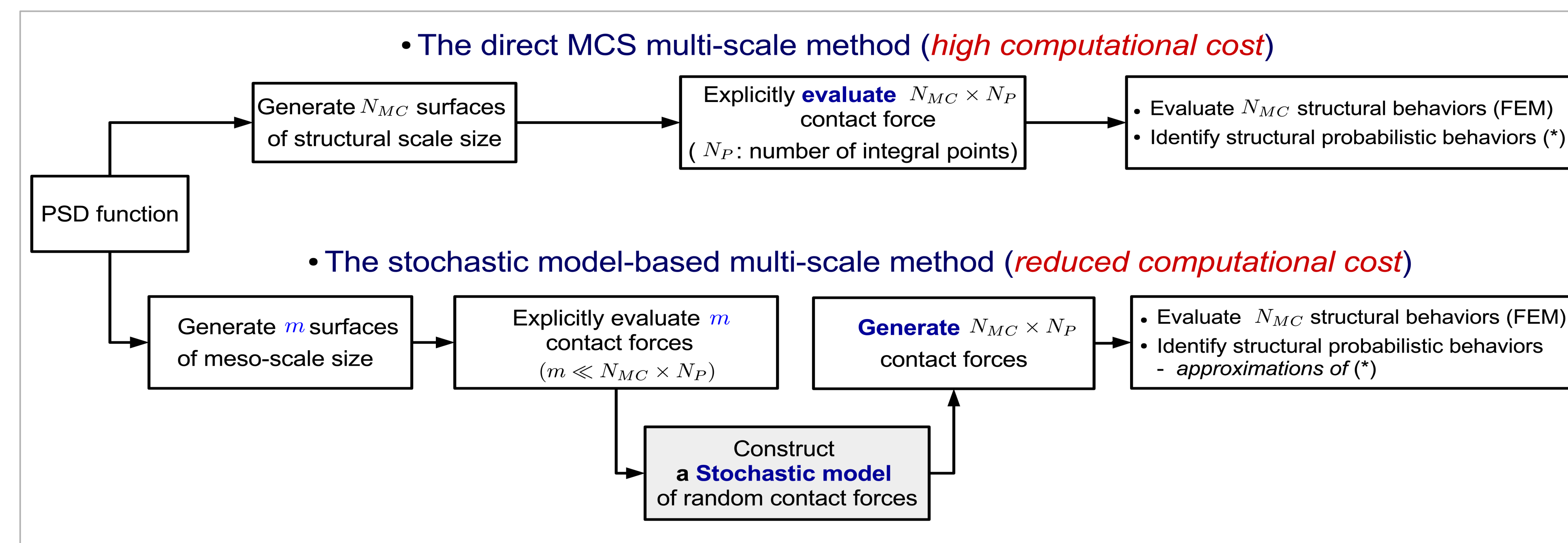
Zoom into the contact zone.



Random apparent adhesive contact forces.

Method

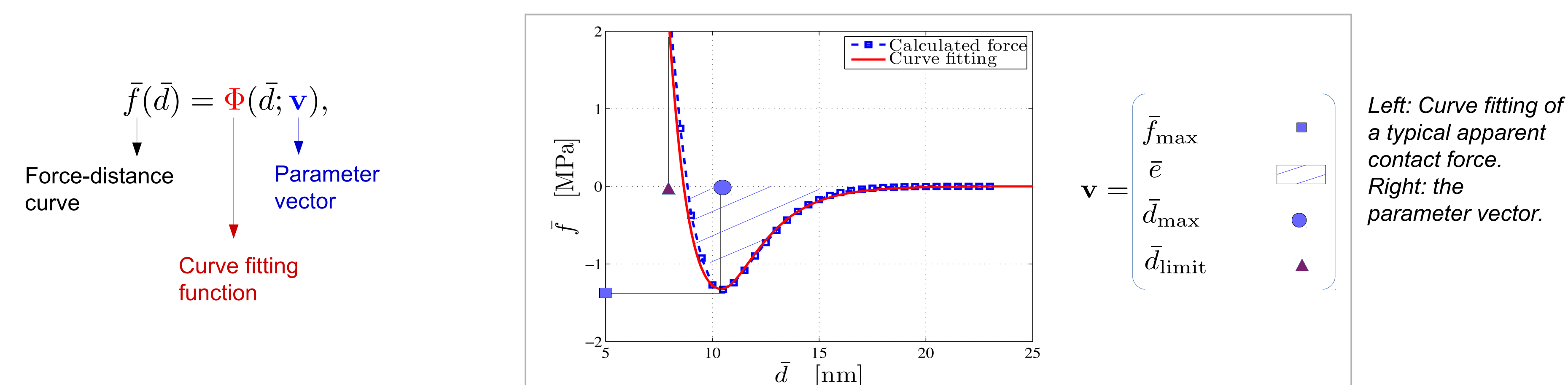
- **Direct Monte Carlo simulation (MCS) multiscale method.**
 - **Characterize** the contact rough surfaces using **power spectrum density (PSD)** and **height distribution**.
 - **Generate** N_{MC} surfaces with size of contact zone.
 - For each generated surface, at each integral point **evaluate** the corresponding meso-scale **apparent contact force**.^(*)
 - Obtain the **failure configuration** for each generated surface.
 - >>> Require **high computational cost** due to step^(*).
- **Proposed method: Stochastic model-based multiscale method**
 - Construct a **stochastic model of apparent contact force**.
 - Each integral point is associated with a generated sample of the random apparent contact forces using the constructed stochastic model.
 - >>> **Reduce computational cost**.



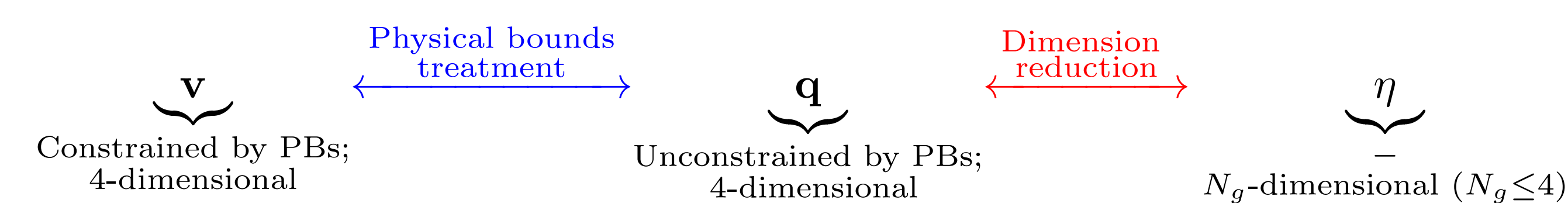
The two uncertainty propagation methods used to evaluate the probabilistic behaviors of structures involving adhesive contacts.

- **Construction of the stochastic model of random apparent contact forces based on generalized polynomial chaos expansion (gPCE) with 3 steps**

- (i) **Parametrization** of the apparent contact forces using an analytical function derived from Morse potential,



- (ii) Data preprocessing procedures: **accounting for the physical bounds (PBs)**, and **dimension reduction** using principle component analysis,



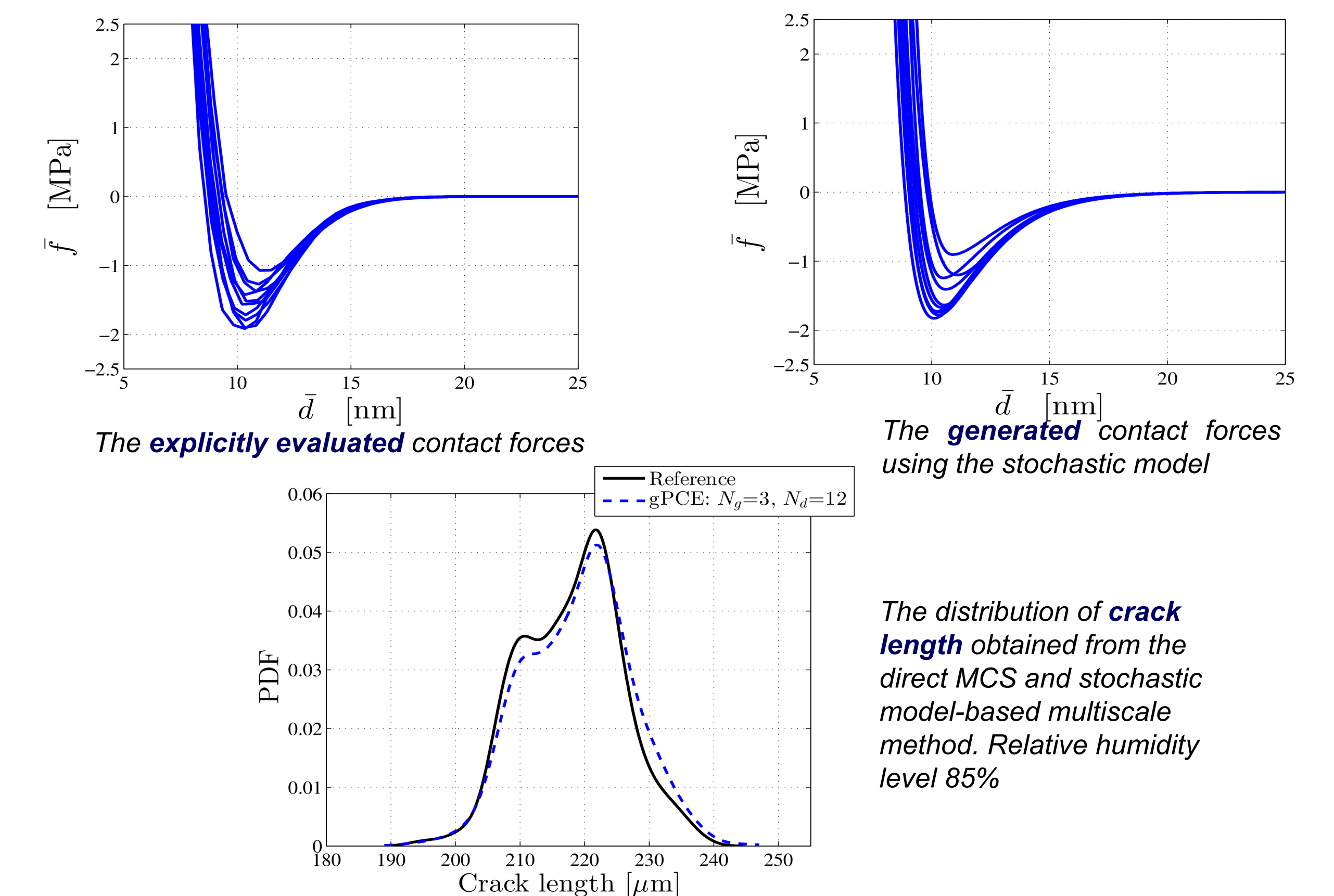
- (iii) Representing the reduced dimension random vector by a **truncated gPCE model**,

$$\eta = \sum_{\alpha=1}^N c_{\alpha} \Psi_{\alpha}(\xi).$$

Coefficients to be identified ← Legendre polynomials → Uniform distributed random vector

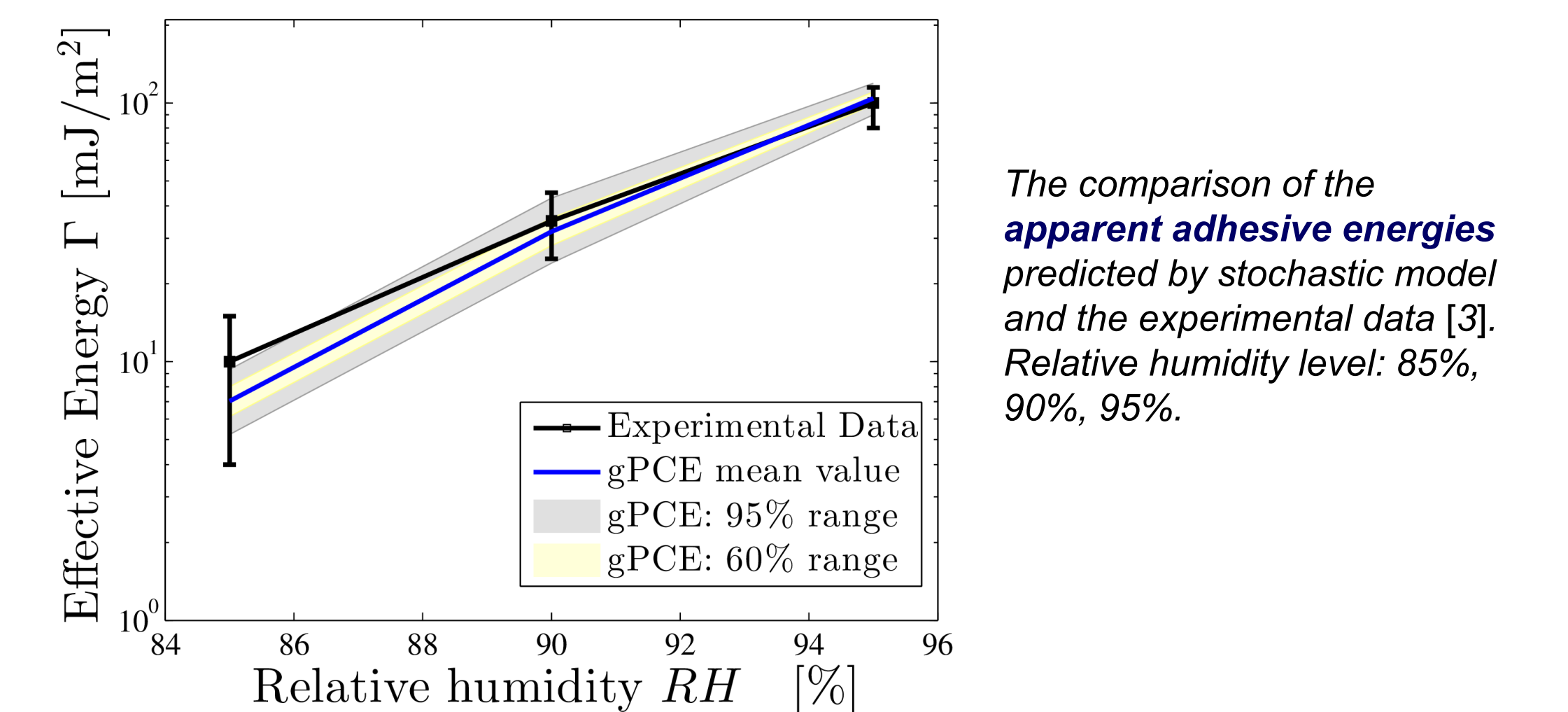
Results

- **Comparison between direct MCS and stochastic model-based methods**
 - The **stochastic model-based method** can **predict the nominate properties** of the crack length distribution.



- **Comparison between numerical prediction and experimental data [3]**

- The **stochastic model-based method** can **predict the experimental results with high accuracy**.



- **Computational effectiveness.** Time to evaluate 1 realization in one CPU:

- Direct MCS: **~16 hours**; Stochastic model-based method: **~5 minutes**.

Conclusions

- A **novel stochastic multiscale method** to predict the probabilistic behaviors of micro structures involving adhesive contacts is developed.
- The model is **computationally effective**.
- The model is validated by a **comparison with experimental data**.

References

- [1] T.-V. Hoang et al., Tribology International, 2016 (submitted).
- [2] T.-V. Hoang et al., Journal of Computational and Applied Mathematics 2015.
- [3] F. W. Delrio et al., In Scanning Probe Microscopy in Nanoscience and Nanotechnology 3, 2013.

Acknowledgments

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